

S-576Z B Series

125°C OPERATION, HIGH-WITHSTAND VOLTAGE, HIGH-SPEED, ZCL™ HALL EFFECT IC

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This IC, developed by CMOS technology, is a high-accuracy Hall effect IC that operates with high temperature and high-withstand voltage.

The IC switches output voltage level when the IC detects magnetic flux density (magnetic field) polarity changes. The ZCL (Zero Crossing Latch) detection method realizes polarity changes detection with the higher accuracy than the conventional bipolar latch method. Using this IC with a magnet makes it possible to detect the rotation status in various devices.

ABLIC Inc. offers a "magnetic simulation service" that provides the ideal combination of magnets and our Hall effect ICs for customer systems. Our magnetic simulation service will reduce prototype production, development period and development costs. In addition, it will contribute to optimization of parts to realize high cost performance.

■ Features

- Uses a thin (t0.80 mm max.) TSOT-23-3S or ultra-thin (t0.50 mm max.) HSNT-6(2025) package, allowing for device miniaturization
- Contributes to reduction of mechanism operation dispersion through high accuracy detection of magnetic flux density (magnetic field) polarity changes
- Contributes to device safe design with a built-in output current limit circuit

■ Specifications

• Pole detection: ZCL detection

• Output logic*1: $V_{OUT} = "L"$ at S pole detection

V_{OUT} = "H" at S pole detection

For more information regarding our magnetic simulation service, contact our sales representatives.

• Output form*1: Nch open-drain output

Nch driver + built-in pull-up resistor (1.2 k Ω typ.) Bz = 0.0 mT typ.

Zero crossing latch point: B_Z = 0.0 mT typ.
 Release point (S pole)*1: B_{RS} = 3.0 mT typ.

 $B_{RS} = 6.0 \text{ mT typ.}$

• Chopping frequency: $f_C = 500 \text{ kHz typ.}$

• Output delay time: $t_D = 8.0 \mu s \text{ typ.}$

Power supply voltage range*2: V_{DD} = 2.7 V to 26.0 V

Built-in regulator

• Built-in output current limit circuit

• Operation temperature range: Ta = -40°C to +125°C

• Lead-free (Sn 100%), halogen-free

*1. The option can be selected.

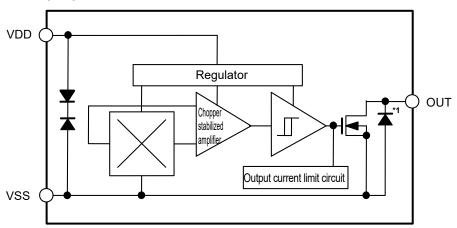
*2. V_{DD} = 2.7 V to 5.5 V when output form is Nch driver + built-in pull-up resistor (1.2 k Ω typ.)

■ Applications

- DC brushless motor
- Home appliance
- Housing equipment
- Industrial equipment
- Packages
- TSOT-23-3S
- HSNT-6(2025)

■ Block Diagrams

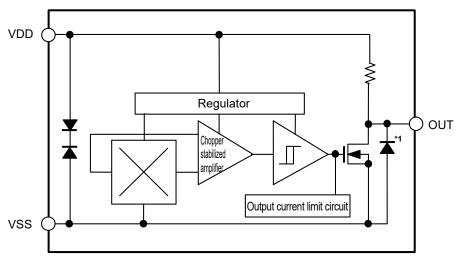
1. Nch open-drain output product



*1. Parasitic diode

Figure 1

2. Nch driver + built-in pull-up resistor product



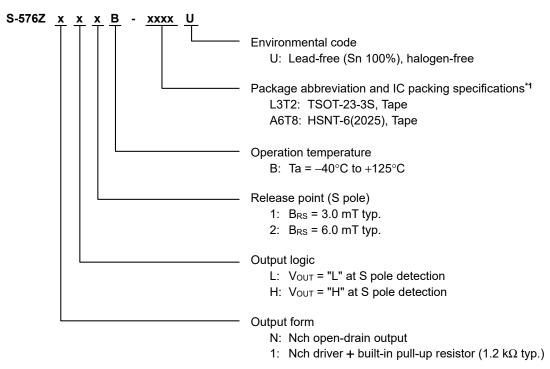
*1. Parasitic diode

Figure 2

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■ Product Name Structure

1. Product name



^{*1.} Refer to the tape drawing.

2. Packages

Table 1 Package Drawing Codes

Package Name	Dimension	Tape	Reel	Land	Stencil Opening
TSOT-23-3S	MP003-E-P-SD	MP003-E-C-SD	MP003-E-R-SD	_	_
HSNT-6(2025)	PJ006-B-P-SD	PJ006-B-C-SD	PJ006-B-R-SD	PJ006-B-LM-SD	PJ006-B-LM-SD

125°C OPERATION, HIGH-WITHSTAND VOLTAGE, HIGH-SPEED, ZCL™ HALL EFFECT IC S-576Z B Series Rev.1.1_00

3. Product name list

3.1 TSOT-23-3S

Table 2

Product Name	Output Form	Power Supply Voltage Range	Output Logic	Release Point (S pole) (B _{RS})
S-576ZNL1B-L3T2U	Nch open-drain output	V _{DD} = 2.7 V to 26.0 V	V _{OUT} = "L" at S pole detection	3.0 mT typ.
S-576Z1L1B-L3T2U	Nch driver + built-in pull-up resistor (1.2 $k\Omega$ typ.)	V _{DD} = 2.7 V to 5.5 V	V _{OUT} = "L" at S pole detection	3.0 mT typ.

Remark Please contact our sales representatives for products other than the above.

3. 2 HSNT-6(2025)

Table 3

Product Name	Output Form	Power Supply Voltage Range	Output Logic	Release Point (S pole) (B _{RS})
S-576ZNL1B-A6T8U	Nch open-drain output	V _{DD} = 2.7 V to 26.0 V	V _{OUT} = "L" at S pole detection	3.0 mT typ.
S-576Z1L1B-A6T8U	Nch driver + built-in pull-up resistor (1.2 $k\Omega$ typ.)	V _{DD} = 2.7 V to 5.5 V	V _{OUT} = "L" at S pole detection	3.0 mT typ.

Remark Please contact our sales representatives for products other than the above.

■ Pin Configurations

1. TSOT-23-3S

Top view



Figure 3

Table 4

Pin No.	Symbol	Description
1	VSS	GND pin
2	VDD	Power supply pin
3	OUT	Output pin

2. HSNT-6(2025)

Top view



Bottom view



Figure 4

Table 5

Pin No.	Symbol	Description
1	VDD	Power supply pin
2	NC*2	No connection
3	OUT	Output pin
4	NC*2	No connection
5	VSS	GND pin
6	NC*2	No connection

- ***1.** Connect the heatsink of backside at shadowed area to the board, and set electric potential open or GND. However, do not use it as the function of electrode.
- ***2.** The NC pin is electrically open.

 The NC pin can be connected to the VDD pin or the VSS pin.

■ Absolute Maximum Ratings

Table 6

	Item	Symbol	Absolute Maximum Rating	Unit
	Nch open-drain output product		$V_{SS} - 0.3$ to $V_{SS} + 28.0$	V
Power supply voltage	Nch driver + built-in pull-up resistor (1.2 k Ω typ.) product	V _{DD}	Vss – 0.3 to Vss + 9.0	V
Power supply current		I _{DD}	±10	mA
Output current		Іоит	±10	mA
	Nch open-drain output product		$V_{SS} - 0.3$ to $V_{SS} + 28.0$	V
Output voltage	Nch driver + built-in pull-up resistor (1.2 k Ω typ.) product	V _{оит}	$V_{\text{SS}} - 0.3 \text{ to } V_{\text{DD}} + 0.3$	V
Operation ambient tem	perature	T _{opr} -40 to +125		°C
Storage temperature		T _{stg}	-40 to +150	°C

Caution The absolute maximum ratings are rated values exceeding which the product could suffer physical damage. These values must therefore not be exceeded under any conditions.

■ Thermal Resistance Value

Table 7

Item	Symbol	Condition		Min.	Тур.	Max.	Unit
			Board A	_	225	-	°C/W
			Board B	_	190	-	°C/W
		TSOT-23-3S	Board C	_	I	-	°C/W
			Board D	_	I	-	°C/W
Junction-to-ambient thermal resistance*1			Board E	_	I	-	°C/W
Junction-to-ambient thermal resistance	θ JA	HSNT-6(2025)	Board A	_	180	-	°C/W
			Board B	_	128	-	°C/W
			Board C	_	43	-	°C/W
			Board D	_	44	_	°C/W
			Board E	_	36	_	°C/W

^{*1.} Test environment: compliance with JEDEC STANDARD JESD51-2A

Remark Refer to "■ **Power Dissipation**" and "**Test Board**" for details.

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■ Electrical Characteristics

1. Nch open-drain output product

Table 8

(Ta = +25°C, V_{DD} = 12.0 V, V_{SS} = 0 V unless otherwise specified)

Item	Symbol	Condition	Min.	Тур.	Max.	Unit	Test Circuit
Power supply voltage	V_{DD}	_	2.7	12.0	26.0	V	_
Current consumption	I_{DD}	_	_	4.0	4.5	mA	1
Low level output voltage	Vol	Іоит = 5 mA, Vоит = "L"	_	_	0.4	V	2
Leakage current	ILEAK	V _{OUT} = "H"	_	_	1.0	μΑ	3
Output limit current	Іом	V _{OUT} = 12.0 V	11	_	35	mA	3
Output delay time*1	t_D	_	_	8	16	μs	_
Chopping frequency*1	fc	_	250	500	_	kHz	_
Start up time*1	t _{PON}	_	_	25	40	μs	4
Output rise time*1	t _R	C = 20 pF, R = 820 Ω	_	_	1.0	μs	5
Output fall time*1	t _F	C = 20 pF, R = 820 Ω	_	_	1.0	μs	5

^{*1.} This item is guaranteed by design.

2. Nch driver + built-in pull-up resistor (1.2 k Ω typ.) product

Table 9

(Ta = +25°C, V_{DD} = 5.0 V, V_{SS} = 0 V unless otherwise specified)

Item	Symbol	Condition	Min.	Тур.	Max.	Unit	Test Circuit
Power supply voltage	V_{DD}	_	2.7	5.0	5.5	V	_
Current consumption	I _{DD}	V _{OUT} = "H"	_	4.0	4.5	mA	1
Low level output voltage	VoL	Iout = 0 mA, Vout = "L"	_	_	0.4	V	2
High level output voltage	V _{OH}	I _{OUT} = 0 mA, V _{OUT} = "H"	$V_{DD} \times 0.9$	_	_	V	2
Output limit current	Іом	$V_{DD} = V_{OUT} = 5.0 \text{ V}$	11	_	35	mA	3
Output delay time*1	t _D	_	_	8	16	μs	_
Chopping frequency*1	fc	_	250	500	_	kHz	_
Start up time*1	t _{PON}	_	_	25	40	μs	4
Output rise time*1	t _R	C = 20 pF	_	_	1.0	μs	5
Output fall time*1	t _F	C = 20 pF	_	_	1.0	μs	5
Pull-up resistor	R_L	_	0.9	1.2	1.5	kΩ	_

^{*1.} This item is guaranteed by design.

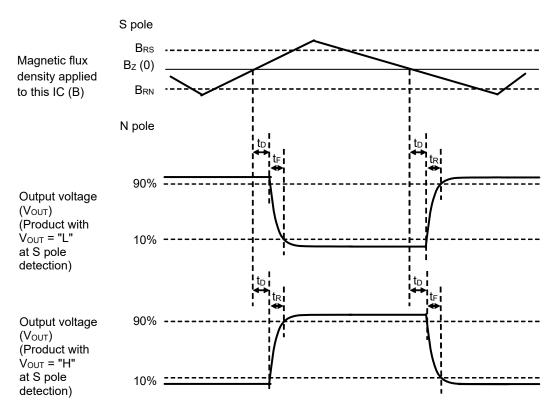


Figure 5 Operation Timing

■ Magnetic Characteristics

1. TSOT-23-3S

1. 1 Product with $B_{RS} = 3.0 \text{ mT typ.}$

Table 10

 $(Ta = +25^{\circ}C, V_{DD} = 5.0 \text{ V}, V_{SS} = 0 \text{ V} \text{ unless otherwise specified})$

			(-,	,			
Item		Symbol	Condition	Min.	Тур.	Max.	Unit	Test Circuit
Zero crossing latch point Bz*1		_	-1.15	0.0	1.15	mT	4	
S pole		B _{RS} *2	-	1.9	3.0	4.1	mT	4
Release point	N pole	B _{RN} *3	_	-4.1	-3.0	-1.9	mT	4

1. 2 Product with $B_{RS} = 6.0 \text{ mT typ.}$

Table 11

(Ta = +25°C, V_{DD} = 5.0 V, V_{SS} = 0 V unless otherwise specified)

Item		Symbol	Condition	Min.	Тур.	Max.	Unit	Test Circuit
Zero crossing latch point Bz*1		_	-1.35	0.0	1.35	mT	4	
S pole		B _{RS} *2	_	4.0	6.0	8.0	mT	4
Release point	N pole	B _{RN} *3	_	-8.0	-6.0	-4.0	mT	4

2. HSNT-6(2025)

2. 1 Product with $B_{RS} = 3.0 \text{ mT typ.}$

Table 12

(Ta = +25°C, V_{DD} = 5.0 V, V_{SS} = 0 V unless otherwise specified)

Item	Item Symbol		Condition	Min.	Тур.	Max.	Unit	Test Circuit
Zero crossing latch p	oint	Bz*1	-			mT	4	
S pole		B _{RS} *2	-	1.0	3.0	5.0	mT	4
Release point	N pole	B _{RN} *3	-	-5.0	-3.0	-1.0	mT	4

2. 2 Product with $B_{RS} = 6.0 \text{ mT typ.}$

Table 13

(Ta = +25°C, V_{DD} = 5.0 V, V_{SS} = 0 V unless otherwise specified)

				-, 55	- ,			
Item		Symbol	Condition	Min.	Тур.	Max.	Unit	Test Circuit
Zero crossing latch point		Bz*1	_	-1.75	0.0	1.75	mT	4
Release point	S pole	B _{RS} *2	_	3.5	6.0	8.5	mT	4
	N pole	B _{RN} *3	_	-8.5	-6.0	-3.5	mT	4

 $[\]star 1.$ B_Z: Zero crossing latch point

B_Z is the value of magnetic flux density at which polarity changes are detected according to the magnetic flux density applied to this IC.

*2. B_{RS}: Release point (S pole)

B_{RS} is the value of magnetic flux density of release point (S pole).

This IC releases the Hold status of the output voltage (V_{OUT}) when the magnetic flux density applied to this IC exceeds B_{RS} (by moving the magnet (S pole) closer).

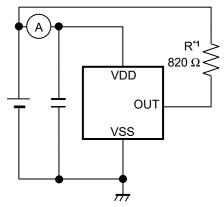
*3. B_{RN}: Release point (N pole)

B_{RN} is the value of magnetic flux density of release point (N pole).

This IC releases the Hold status of the output voltage (V_{OUT}) when the magnetic flux density applied to this IC exceeds B_{RN} (by moving the magnet (N pole) closer).

Remark The unit of magnetic density mT can be converted by using the formula 1 mT = 10 Gauss.

■ Test Circuits



***1.** Resistor (R) is unnecessary for Nch driver + built-in pull-up resistor product.

Figure 6 Test Circuit 1

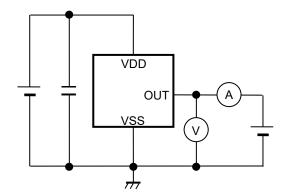
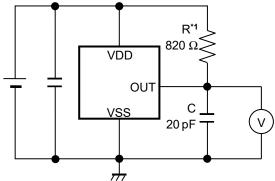


Figure 8 Test Circuit 3



***1.** Resistor (R) is unnecessary for Nch driver + built-in pull-up resistor product.

Figure 10 Test Circuit 5

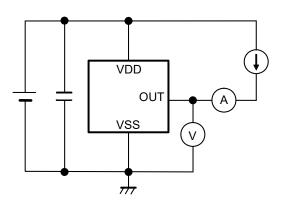
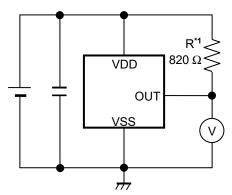


Figure 7 Test Circuit 2

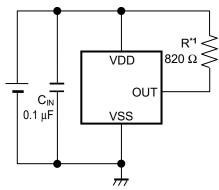


*1. Resistor (R) is unnecessary for Nch driver + built-in pull-up resistor product.

Figure 9 Test Circuit 4

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■ Standard Circuit



*1. Resistor (R) is unnecessary for Nch driver + built-in pull-up resistor product.

Figure 11

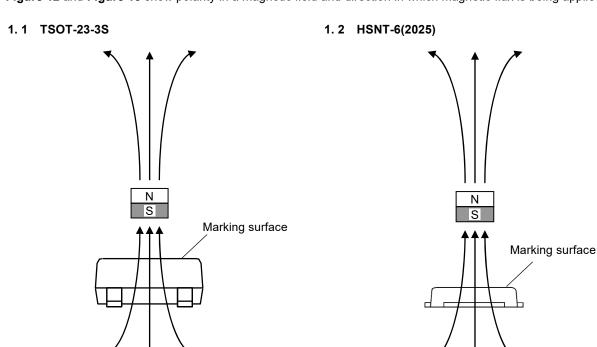
Caution The above connection diagram and constants will not guarantee successful operation. Perform thorough evaluation using the actual application to set the constants.

■ Operation

1. Direction of applied magnetic flux

This IC detects the magnetic flux density which is perpendicular to the package marking surface. A magnetic field is defined as positive when marking side of the package is the S pole, and negative when it is the N pole.

Figure 12 and Figure 13 show polarity in a magnetic field and direction in which magnetic flux is being applied.



2. Position of Hall sensor

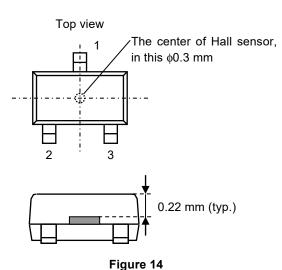
Figure 14 and Figure 15 show the position of Hall sensor.

Figure 12

The center of this Hall sensor is located in the area indicated by a circle, which is in the center of a package as described below.

The following also shows the distance (typ. value) between the marking surface and the chip surface of a package.

2. 1 TSOT-23-3S



2. 2 HSNT-6(2025)

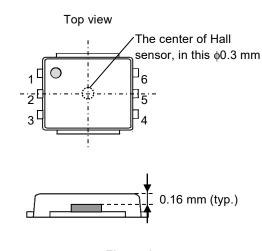


Figure 13

Figure 15

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3. Basic operation

This IC switches output voltage level (V_{OUT}) when the IC detects magnetic flux density (magnetic field) polarity changes by using ZCL technology. ZCL technology realizes polarity changes detection and hold operation (Hold status) of V_{OUT} . This is different from the conventional bipolar latch method. ZCL detection method has no hysteresis width of the magnetic sensitivity to switch V_{OUT} . Instead, the ZCL detection method can switch V_{OUT} without chattering by using the Hold status.

3. 1 ZCL basic operation

This IC switches V_{OUT} after the output delay time (t_D) from when the magnetic flux density applied to this IC crosses B_Z (from B > B_{RS} to B < B_Z or from B < B_{RN} to B > B_Z). When V_{OUT} is switched, this IC starts the Hold status. In the Hold status of V_{OUT} , when the magnetic flux density applied to this IC exceeds B_{RS} or B_{RN}, this IC releases the Hold status (from B < B_Z to B < B_{RN} or from B > B_Z to B > B_{RS}).

Figure 16 and Figure 17 show the V_{OUT} operation timing when sine wave magnetic flux density is applied to this IC.

- (1) $B > B_{RS} \rightarrow B < B_Z$, and after t_D , V_{OUT} = "L" \rightarrow "H", and Hold status starts
- (2) $B < B_Z \rightarrow B < B_{RN}$, and after t_D , Hold status is released, and V_{OUT} = "H" continues
- (3) B < B_{RN} \rightarrow B > B_Z, and after $t_D,\,V_{OUT}$ = "H" \rightarrow "L", and Hold status starts
- (4) $B > B_Z \rightarrow B > B_{RS}$, and after t_D , Hold status is released, and V_{OUT} = "L" continues

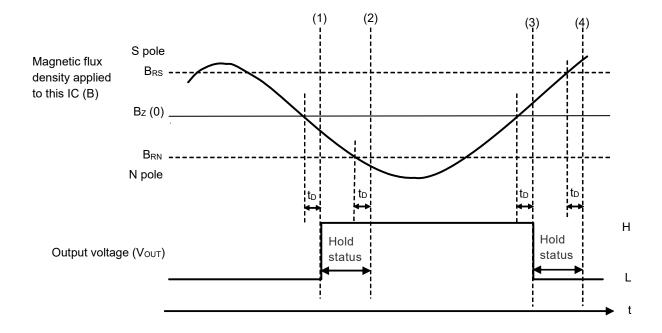


Figure 16 Product with V_{OUT} = "L" at S pole detection

- (1) $B > B_{RS} \rightarrow B < B_Z$, and after t_D , V_{OUT} = "H" \rightarrow "L", and Hold status starts
- (2) $B < B_Z \rightarrow B < B_{RN}$, and after t_D , Hold status is released, and V_{OUT} = "L" continues
- (3) B < B_{RN} \rightarrow B > Bz, and after t_D, V_{OUT} = "L" \rightarrow "H", and Hold status starts
- (4) $B > B_Z \rightarrow B > B_{RS}$, and after t_D , Hold status is released, and V_{OUT} = "H" continues

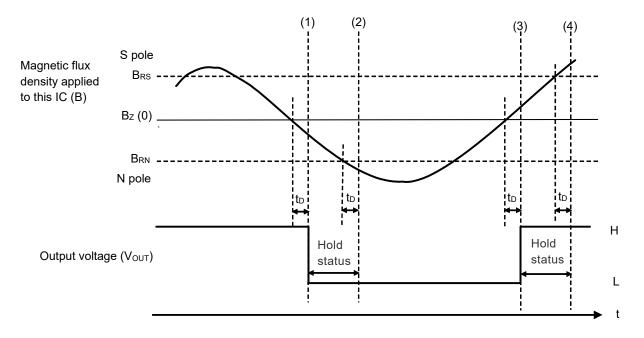


Figure 17 Product with V_{OUT} = "H" at S pole detection

3. 2 Prevention of VouT chattering by Hold status

By the Hold status, this IC can switch V_{OUT} without chattering even under an influence of external mechanical vibrations, electrical noise, or magnetic noise.

Figure 18 and Figure 19 show the V_{OUT} operation when the magnetic flux density applied to this IC changes near the zero crossing latch point (Bz) and Bz is crossed multiple times.

(1) In the Hold status, the IC retains V_{OUT} when the magnetic flux density applied to this IC crosses B_Z.

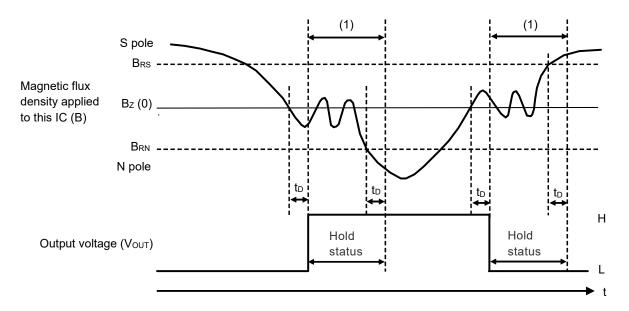


Figure 18 Product with V_{OUT} = "L" at S pole detection

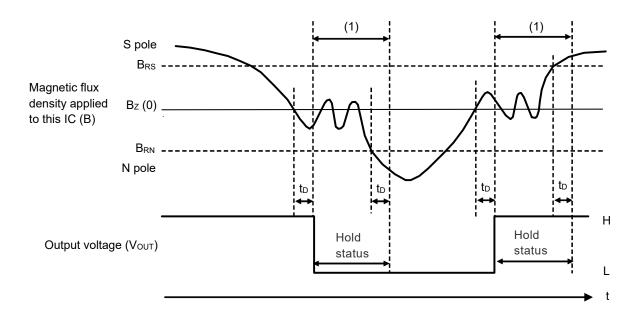


Figure 19 Product with V_{OUT} = "H" at S pole detection

3. 3 Operation when polarity changes direction is inverted in the Hold status

In the Hold status, when the polarity changes direction is inverted, this IC release the Hold status at the opposite release point and switches V_{OUT} .

Figure 20 and Figure 21 show the Vout operation timing when the polarity change direction is inverted.

- (1) B > Bz \rightarrow B < Bz, and after t_D, V_{OUT} = "L" \rightarrow "H", and Hold status starts
- (2) During Hold status, even after $B < B_Z \rightarrow B > B_Z$, $V_{OUT} = "H"$ is retained
- (3) $B > B_Z \rightarrow B > B_{RS}$, and after t_D, Hold status is released, and $V_{OUT} = "H" \rightarrow "L"$
- (4) B < Bz \rightarrow B > Bz, and after t_D, V_{OUT} = "H" \rightarrow "L", and Hold status starts
- (5) During Hold status, even after $B > B_Z \rightarrow B < B_Z$, V_{OUT} = "L" is retained
- (6) B < Bz \rightarrow B < B_{RN}, and after t_D, Hold status is released, and V_{OUT} = "L" \rightarrow "H"

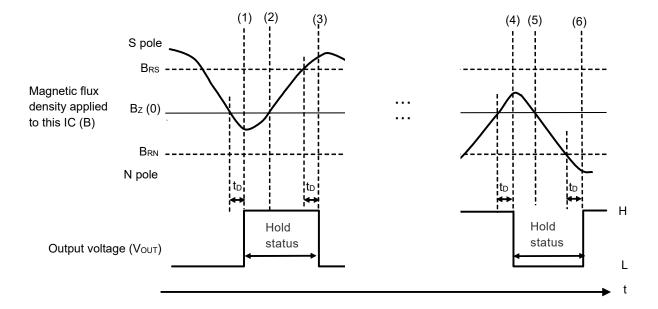


Figure 20 Product with V_{OUT} = "L" at S pole detection

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- (1) $B > B_Z \rightarrow B < B_Z$, and after t_D , V_{OUT} = "H" \rightarrow "L", and Hold status starts
- (2) During Hold status, even after $B < B_Z \rightarrow B > B_Z$, V_{OUT} = "L" is retained
- (3) B > Bz \rightarrow B > BRS, and after t_D, Hold status is released, and V_{OUT} = "L" \rightarrow "H"
- (4) B < Bz \rightarrow B > Bz, and after t_D, V_{OUT} = "L" \rightarrow "H", and Hold status starts
- (5) During Hold status, even after B > Bz \rightarrow B < Bz, VouT = "H" is retained
- (6) B < Bz ightarrow B < B_{RN}, and after t_D, Hold status is released, and V_{OUT} = "H" ightarrow "L"

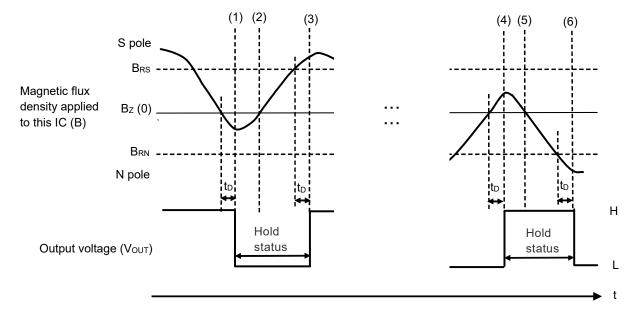


Figure 21 Product with V_{OUT} = "H" at S pole detection

4. Power-on operation

This IC requires start up time (t_{PON}) during the time immediately after power-on until V_{OUT} switches. During the t_{PON} period, V_{OUT} is "H". After t_{PON} , when $B > B_{RS}$ or $B < B_{RN}$ is detected, polarity changes can be detected.

4. 1 B > B_{RS} or B < B_{RN}

When the magnetic flux density applied to this IC at power-on is $B > B_{RS}$ or $B < B_{RN}$, after t_{PON} , V_{OUT} switches according to the output logic at the S pole detection, and polarity changes can be detected.

Figure 22 and Figure 23 show V_{OUT} operation immediately after power-on when $B > B_{RS}$ or $B < B_{RN}$.

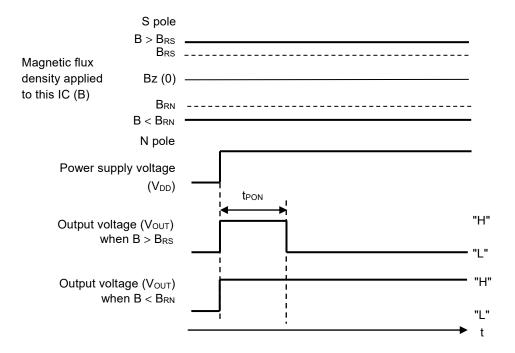


Figure 22 Product with $V_{OUT} = "L"$ at S pole detection

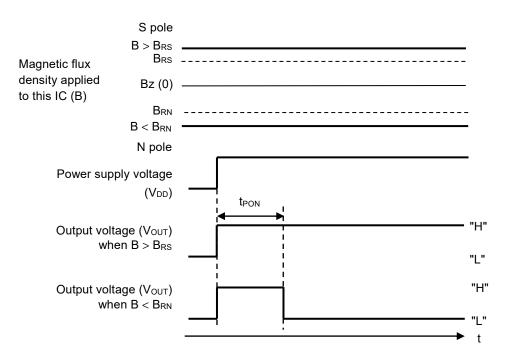


Figure 23 Product with V_{OUT} = "H" at S pole detection ABLIC Inc.

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4. 2 BRN < B < BRS

When the magnetic flux density applied to this IC at power-on is $B_{RN} < B < B_{RS}$, after t_{PON} , V_{OUT} continues "H". Thereafter, when the magnetic flux density changes to $B > B_{RS}$ or $B < B_{RN}$, after t_D , V_{OUT} switches according to the output logic at the S pole detection and magnetic flux density, and polarity changes can be detected.

Figure 24 and **Figure 25** show V_{OUT} operation when change of $B_{RN} < B < B_{RS} \rightarrow B > B_{RS}$ or $B < B_{RN}$ occurs after t_{PON} .

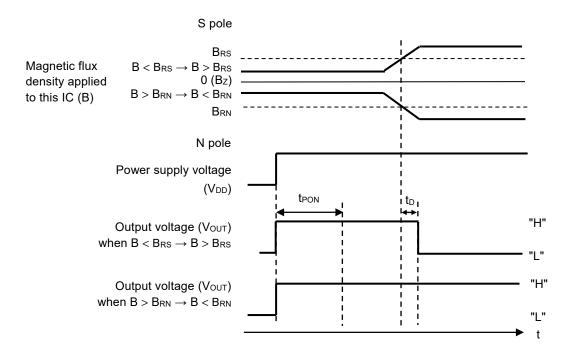


Figure 24 Product with $V_{OUT} = "L"$ at S pole detection

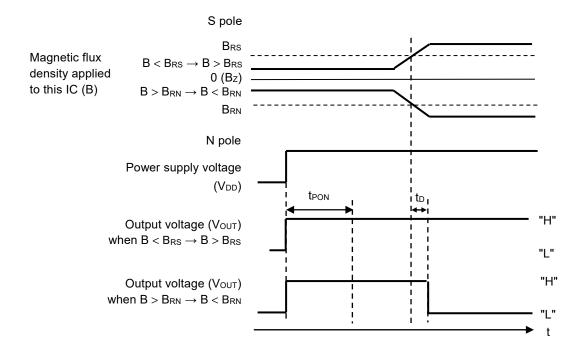


Figure 25 Product with Vout = "H" at S pole detection

■ Precautions

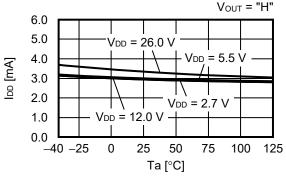
- If the impedance of the power supply is high, the IC may malfunction due to a supply voltage drop caused by feed-through current. Take care with the pattern wiring to ensure that the impedance of the power supply is low.
- Note that the IC may malfunction if the power supply voltage rapidly changes. When the IC is used under the
 environment where the power supply voltage rapidly changes, it is recommended to judge the output voltage of
 the IC by reading it multiple times.
- Do not apply an electrostatic discharge to this IC that exceeds the performance ratings of the built-in electrostatic protection circuit.
- Although this IC has a built-in output current limit circuit, it may suffer physical damage such as product deterioration under the environment where the absolute maximum ratings are exceeded.
- The application conditions for the power supply voltage, the pull-up voltage, and the pull-up resistor should not exceed the power dissipation.
- Large stress on this IC may affect the magnetic characteristics. Avoid large stress which is caused by the handling during or after mounting the IC on a board.
- Since the package heat radiation differs according to the conditions of the application, perform thorough evaluation with actual applications to confirm no problems occur.
- ABLIC Inc. claims no responsibility for any disputes arising out of or in connection with any infringement by products including this IC of patents owned by a third party.

■ Characteristics (Typical Data)

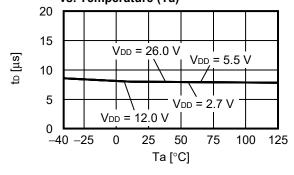
1. Electrical Characteristics

1.1 S-576ZxxxB

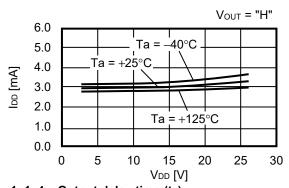
1. 1. 1 Current consumption (I_{DD}) vs. Temperature (Ta)



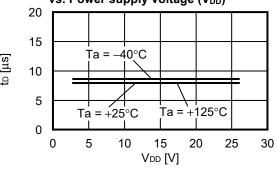
1. 1. 3 Output delay time (t_D) vs. Temperature (Ta)



1. 1. 2 Current consumption (I_{DD}) vs. Power supply voltage (V_{DD})



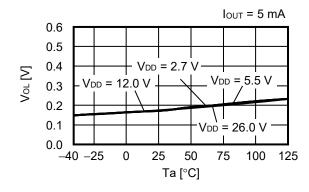
1. 1. 4 Output delay time (t_D) vs. Power supply voltage (V_{DD})



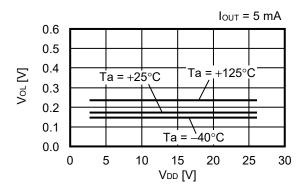
Caution V_{DD} = 2.7 V to 5.5 V when output form is Nch driver + built-in pull-up resistor (1.2 k Ω typ.). Comply with power supply voltage range and do not exceed absolute maximum ratings.

1. 2 S-576ZNxxB

1. 2. 1 Low level output voltage (V_{OL}) vs. Temperature (Ta)

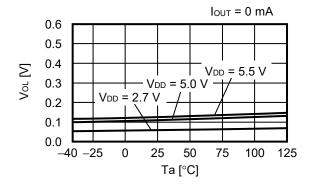


1. 2. 2 Low level output voltage (V_{OL}) vs. Power supply voltage (V_{DD})

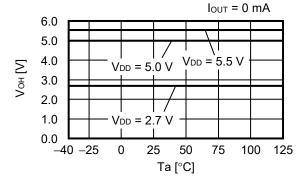


1. 3 S-576Z1xxB

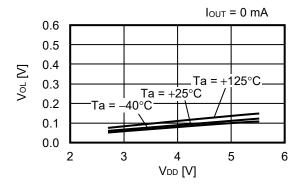
1. 3. 1 Low level output voltage (V_{OL}) vs. Temperature (Ta)



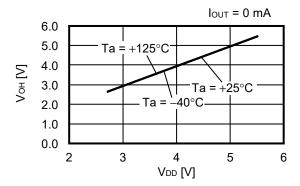
1. 3. 3 High level output voltage (V_{OH}) vs. Temperature (Ta)



1. 3. 2 Low level output voltage (V_{OL}) vs. Power supply voltage (V_{DD})



1. 3. 4 High level output voltage (V_{OH}) vs. Power supply voltage (V_{DD})

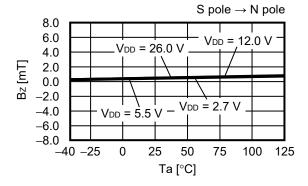


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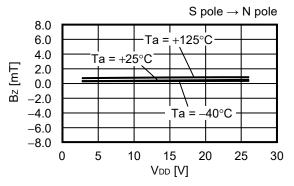
2. Magnetic Characteristics

2. 1 S-576Zxx1B-L3T2U

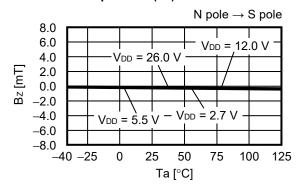
2. 1. 1 Zero crossing latch point (B_z) vs. Temperature (Ta)



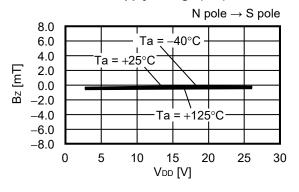
2. 1. 2 Zero crossing latch point (Bz) vs. Power supply voltage (V_{DD})



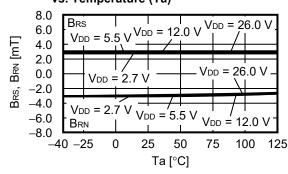
2. 1. 3 Zero crossing latch point (B_z) vs. Temperature (Ta)



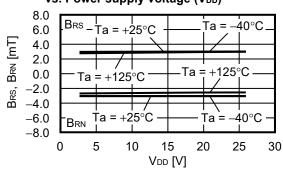
2. 1. 4 Zero crossing latch point (B_Z) vs. Power supply voltage (V_{DD})



2. 1. 5 Release point (B_{RS}, B_{RN}) vs. Temperature (Ta)



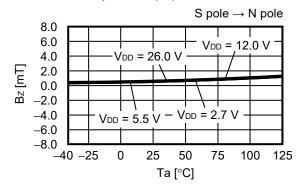
2. 1. 6 Release point (B_{RS}, B_{RN}) vs. Power supply voltage (V_{DD})



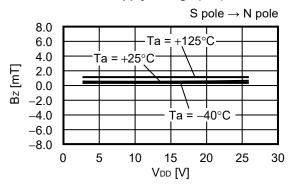
Caution $V_{DD} = 2.7 \text{ V}$ to 5.5 V when output form is Nch driver + built-in pull-up resistor (1.2 k Ω typ.). Comply with power supply voltage range and do not exceed absolute maximum ratings.

2. 2 S-576Zxx2B-L3T2U

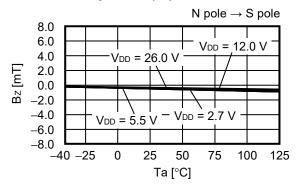
2. 2. 1 Zero crossing latch point (B_z) vs. Temperature (Ta)



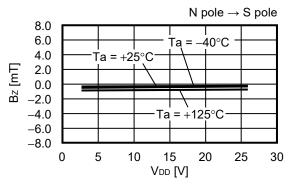
2. 2. 2 Zero crossing latch point (B_Z) vs. Power supply voltage (V_{DD})



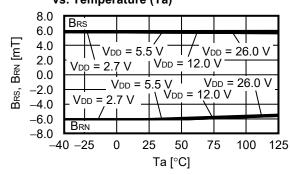
2. 2. 3 Zero crossing latch point (B_z) vs. Temperature (Ta)



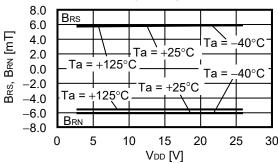
2. 2. 4 Zero crossing latch point (Bz) vs. Power supply voltage (VDD)



2. 2. 5 Release point (B_{RS}, B_{RN}) vs. Temperature (Ta)



2. 2. 6 Release point (B_{RS}, B_{RN}) vs. Power supply voltage (V_{DD})

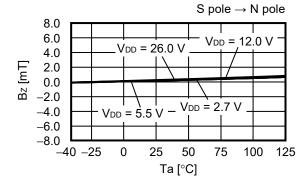


Caution $V_{DD} = 2.7 \text{ V}$ to 5.5 V when output form is Nch driver + built-in pull-up resistor (1.2 k Ω typ.). Comply with power supply voltage range and do not exceed absolute maximum ratings.

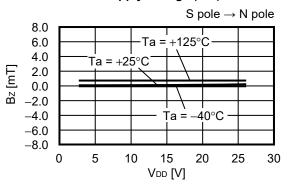
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2. 3 S-576Zxx1B-A6T8U

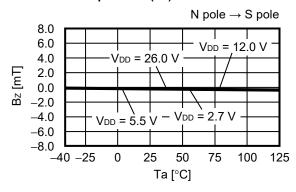
2. 3. 1 Zero crossing latch point (Bz) vs. Temperature (Ta)



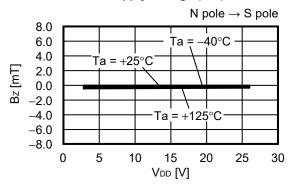
2. 3. 2 Zero crossing latch point (Bz) vs. Power supply voltage (V_{DD})



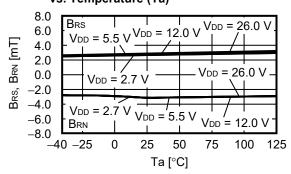
2. 3. 3 Zero crossing latch point (Bz) vs. Temperature (Ta)



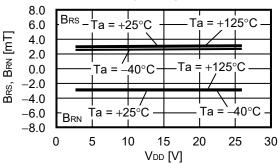
2. 3. 4 Zero crossing latch point (Bz) vs. Power supply voltage (V_{DD})



2. 3. 5 Release point (B_{RS}, B_{RN}) vs. Temperature (Ta)



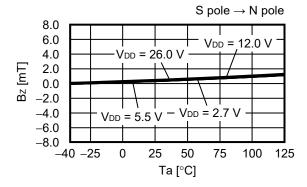
2. 3. 6 Release point (B_{RS}, B_{RN}) vs. Power supply voltage (V_{DD})



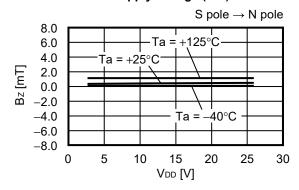
Caution $V_{DD} = 2.7 \text{ V}$ to 5.5 V when output form is Nch driver + built-in pull-up resistor (1.2 k Ω typ.). Comply with power supply voltage range and do not exceed absolute maximum ratings.

2. 4 S-576Zxx2B-A6T8U

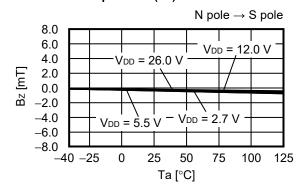
2. 4. 1 Zero crossing latch point (B_z) vs. Temperature (Ta)



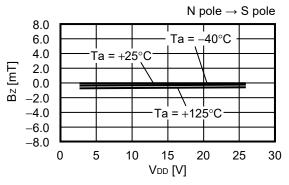
2. 4. 2 Zero crossing latch point (B_Z) vs. Power supply voltage (V_{DD})



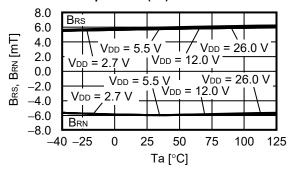
2. 4. 3 Zero crossing latch point (Bz) vs. Temperature (Ta)



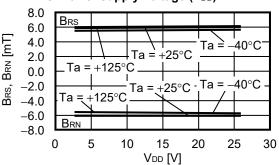
 4. 4 Zero crossing latch point (Bz) vs. Power supply voltage (V_{DD})



2. 4. 5 Release point (B_{RS}, B_{RN}) vs. Temperature (Ta)



2. 4. 6 Release point (B_{RS}, B_{RN}) vs. Power supply voltage (V_{DD})

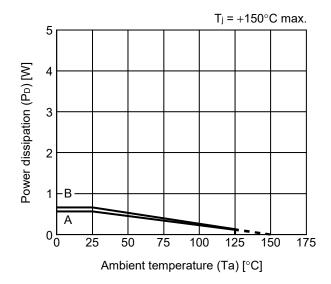


Caution $V_{DD} = 2.7 \text{ V}$ to 5.5 V when output form is Nch driver + built-in pull-up resistor (1.2 k Ω typ.). Comply with power supply voltage range and do not exceed absolute maximum ratings.

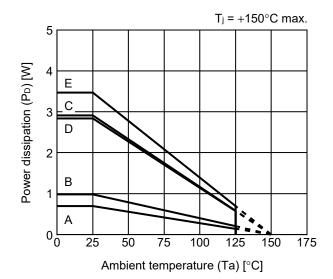
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■ Power Dissipation

TSOT-23-3S



HSNT-6(2025)



 Board
 Power Dissipation (P₀)

 A
 0.56 W

 B
 0.66 W

 C

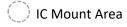
 D

 E

Board	Power Dissipation (P _D)		
Α	0.69 W		
В	0.98 W		
С	2.91 W		
D	2.84 W		
Е	3.47 W		

TSOT-23-3S Test Board

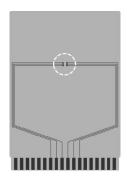
(1) Board A





Item		Specification		
Size [mm]		114.3 x 76.2 x t1.6		
Material		FR-4		
Number of copper foil la	ayer	2		
	1	Land pattern and wiring for testing: t0.070		
Coppor foil layer [mm]	2	-		
Copper foil layer [mm]	3	-		
	4	74.2 x 74.2 x t0.070		
Thermal via		-		

(2) Board B



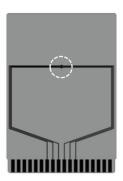
Item		Specification		
Size [mm]		114.3 x 76.2 x t1.6		
Material		FR-4		
Number of copper foil la	ayer	4		
	1	Land pattern and wiring for testing: t0.070		
Copper foil layer [mm]	2	74.2 x 74.2 x t0.035		
Copper foli layer [IIIII]	3	74.2 x 74.2 x t0.035		
	4	74.2 x 74.2 x t0.070		
Thermal via		-		

No. TSOT23x-A-Board-SD-1.0

HSNT-6(2025) Test Board

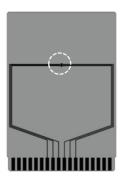
O IC Mount Area

(1) Board A



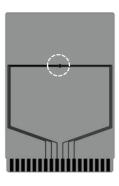
Item		Specification		
Size [mm]		114.3 x 76.2 x t1.6		
Material		FR-4		
Number of copper foil la	ayer	2		
	1	Land pattern and wiring for testing: t0.070		
Copper foil layer [mm]	2	-		
Copper foli layer [IIIII]	3	-		
	4	74.2 x 74.2 x t0.070		
Thermal via		-		

(2) Board B



Item		Specification		
Size [mm]		114.3 x 76.2 x t1.6		
Material		FR-4		
Number of copper foil layer		4		
0	1	Land pattern and wiring for testing: t0.070		
	2	74.2 x 74.2 x t0.035		
Copper foil layer [mm]	3	74.2 x 74.2 x t0.035		
	4	74.2 x 74.2 x t0.070		
Thermal via		-		

(3) Board C



Item		Specification		
Size [mm]		114.3 x 76.2 x t1.6		
Material		FR-4		
Number of copper foil la	ayer	4		
	1	Land pattern and wiring for testing: t0.070		
Connor foil lover [mm]	2	74.2 x 74.2 x t0.035		
Copper foil layer [mm]	3	74.2 x 74.2 x t0.035		
	4	74.2 x 74.2 x t0.070		
Thermal via		Number: 4 Diameter: 0.3 mm		

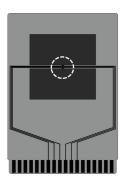


No. HSNT6-B-Board-SD-1.0

HSNT-6(2025) Test Board

O IC Mount Area

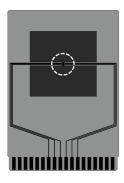
(4) Board D



Item		Specification		
Size [mm]		114.3 x 76.2 x t1.6		
Material		FR-4		
Number of copper foil layer		4		
	1	Pattern for heat radiation: 2000mm ² t0.070		
Coppor foil layer [mm]	2	74.2 x 74.2 x t0.035		
Copper foil layer [mm]	3	74.2 x 74.2 x t0.035		
	4	74.2 x 74.2 x t0.070		
Thermal via		-		



(5) Board E

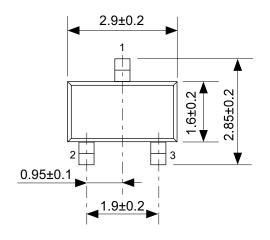


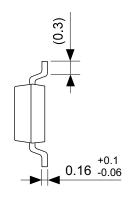
Item		Specification		
Size [mm]		114.3 x 76.2 x t1.6		
Material		FR-4		
Number of copper foil la	ayer	4		
	1	Pattern for heat radiation: 2000mm ² t0.070		
Copper foil layer [mm]	2	74.2 x 74.2 x t0.035		
Copper foil layer [min]	3	74.2 x 74.2 x t0.035		
	4	74.2 x 74.2 x t0.070		
Thermal via		Number: 4 Diameter: 0.3 mm		

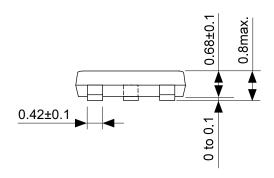


enlarged view

No. HSNT6-B-Board-SD-1.0

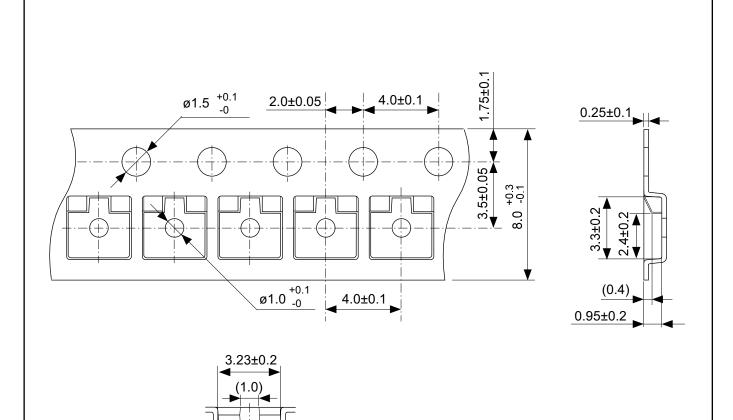


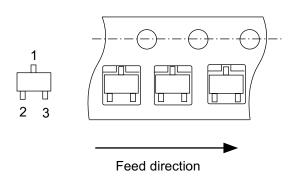




No. MP003-E-P-SD-1.0

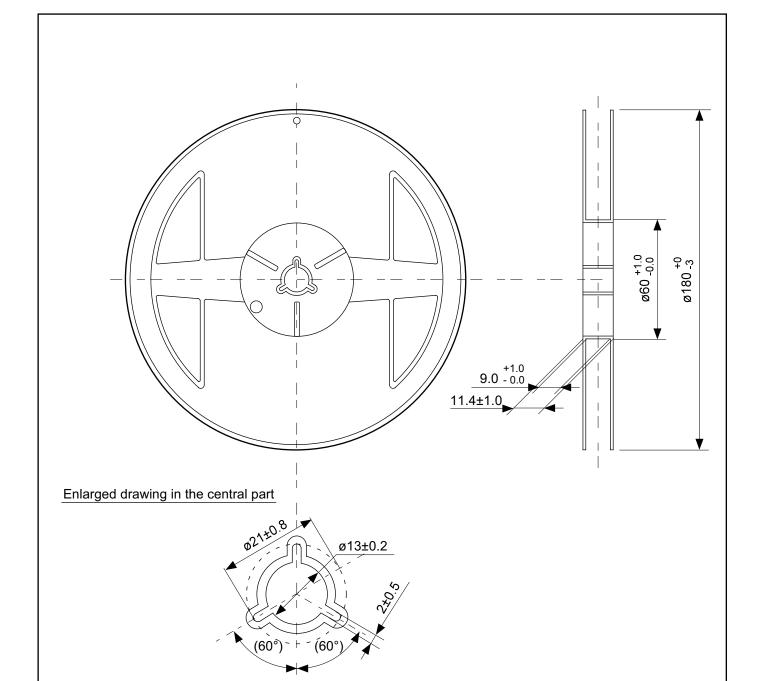
TITLE	TSOT233S-A-PKG Dimensions				
No.	MP003-E-P-SD-1.0				
ANGLE	$\bigoplus \Box$				
UNIT	mm				
ABLIC Inc.					





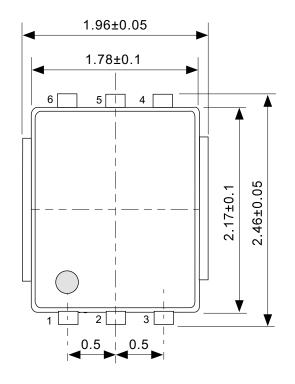
No. MP003-E-C-SD-1.0

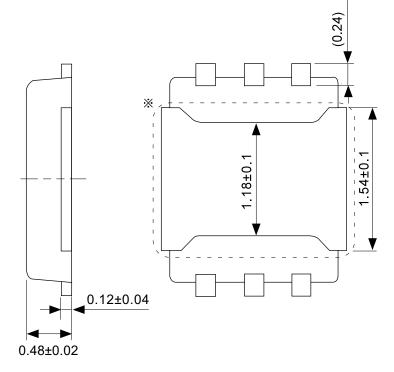
TITLE	TSOT233S-A-Carrier Tape			
No.	MP003-E-C-SD-1.0			
ANGLE				
UNIT	mm			
ABLIC Inc.				

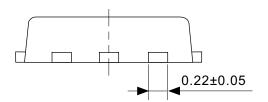


No. MP003-E-R-SD-1.0

TITLE	TSOT233S-A-Reel					
No.	MP003-E-R-SD-1.0					
ANGLE	QTY. 3,000					
UNIT	mm					
ABLIC Inc.						



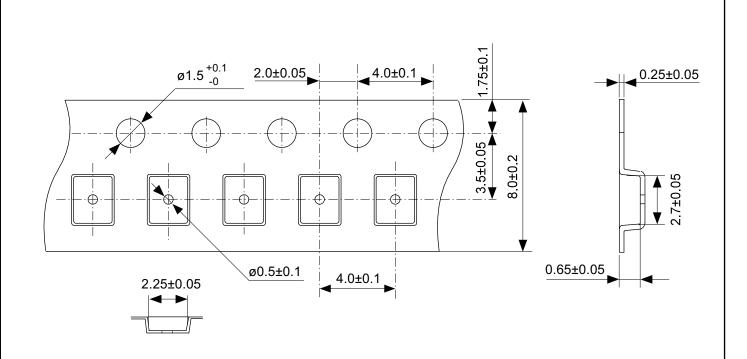


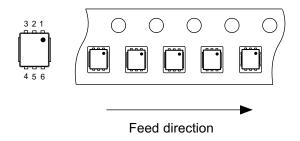


The heat sink of back side has different electric potential depending on the product.
 Confirm specifications of each product.
 Do not use it as the function of electrode.

No. PJ006-B-P-SD-1.0

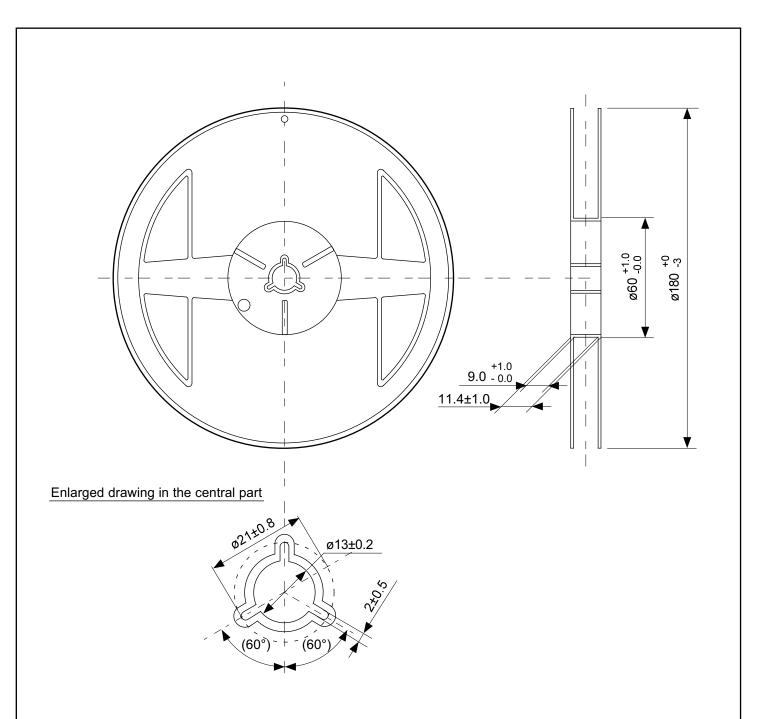
TITLE	HSNT-6-C-PKG Dimensions	
No.	PJ006-B-P-SD-1.0	
ANGLE	\oplus	
UNIT	mm	
ABLIC Inc.		





No. PJ006-B-C-SD-1.0

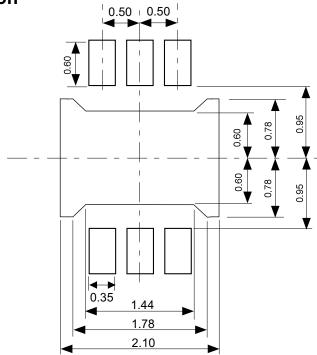
TITLE	HSNT-6-C-Carrier Tape	
No.	PJ006-B-C-SD-1.0	
ANGLE		
UNIT	mm	
ABLIC Inc.		



No. PJ006-B-R-SD-1.0

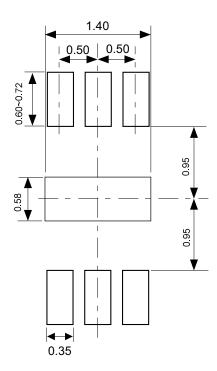
TITLE	HSNT-6-C-Reel			
No.	PJ006-B-R-SD-1.0			
ANGLE		QTY.	5,000	
UNIT	mm			
ABLIC Inc.				

Land Recommendation



Caution It is recommended to solder the heat sink to a board in order to ensure the heat radiation. 注意 放熱性を確保する為に、PKGの裏面放熱板(ヒートシンク)を基板に半田付けする事を推奨いたします。

Stencil Opening



No. PJ006-B-LM-SD-1.0

- Caution ① Mask aperture ratio of the lead mounting part is 100~120%.
 - 2 Mask aperture ratio of the heat sink mounting part is 30%.
 - 3 Mask thickness: t0.12 mm
 - 4 Reflow atmosphere: Nitrogen atmosphere is recommended. (Oxygen concentration: 1000ppm or less)

- 注意 ①リード実装部のマスク開口率は100~120%です。
 - ②放熱板実装のマスク開口率は30%です。
 - ③マスク厚み: t0.12 mm
 - ④リフロー雰囲気・窒素雰囲気(酸素濃度1000ppm以下)推奨

TITLE	HSNT-6-C -Land &Stencil Opening	
No.	PJ006-B-LM-SD-1.0	
ANGLE		
UNIT	mm	
ABLIC Inc.		

Disclaimers (Handling Precautions)

- 1. All the information described herein (product data, specifications, figures, tables, programs, algorithms and application circuit examples, etc.) is current as of publishing date of this document and is subject to change without notice.
- 2. The circuit examples and the usages described herein are for reference only, and do not guarantee the success of any specific mass-production design.
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- 3. ABLIC Inc. is not liable for any losses, damages, claims or demands caused by the incorrect information described herein.
- 4. Be careful to use the products within their ranges described herein. Pay special attention for use to the absolute maximum ratings, operation voltage range and electrical characteristics, etc.
 - ABLIC Inc. is not liable for any losses, damages, claims or demands caused by failures and / or accidents, etc. due to the use of the products outside their specified ranges.
- 5. Before using the products, confirm their applications, and the laws and regulations of the region or country where they are used and verify suitability, safety and other factors for the intended use.
- 6. When exporting the products, comply with the Foreign Exchange and Foreign Trade Act and all other export-related laws, and follow the required procedures.
- 7. The products are strictly prohibited from using, providing or exporting for the purposes of the development of weapons of mass destruction or military use. ABLIC Inc. is not liable for any losses, damages, claims or demands caused by any provision or export to the person or entity who intends to develop, manufacture, use or store nuclear, biological or chemical weapons or missiles, or use any other military purposes.
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